FORM PTO-1449

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LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT

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Filing Date Group Art: April 1, 2004

## U.S. PATENT DOCUMENTS

Examiner Initial		Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
/JV/	AA	6,574,778	06/2003	Chang et al. 716	716	1	
1	AB	6,578,174	06/2003	Zizzo	716	1	
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AG						

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

/JV/	AH	Sutherland, S.; "The IEEE Verilog 1364-2001 Standard What's New, and Why You Need It," 9th Annual International HDL Conference and Exhibition, March 2000. Pp. 1-8.			
	AI	Cummings, C.; "Verilog-2001 Behavior 2002, pp. 1-23.	ral and Synthesis Enhancements," Revised April		
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<b>V</b>	AJ	Miodrag Potkonjak et al. "Behavioral Synthesis of Area-Efficient Testable Designs Using Interaction Between Hardware Sharing and Partial Scan," IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, vol. 14, no. 9, September 1995, pp. 1141-1154.			
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EXAMIN	ER:	/Jasjit Vidwan/	DATE CONSIDERED: 05/28/2007		

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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